Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.		SERIAL NO.		
(Modified)		PATENT AND TRADEMARK OFFICE		243057US2SRD	New Application			
				APPLICANT				
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Munehiro OGASAWARA				
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U.S. PATENT DOCUMENTS								
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
4.2	AO	7-61185	03/20/95	JAPAN	-,			X
1111	AP	2001-34115	02/09/2001	JAPAN				x
20	AQ	2001-217173	08/10/2001	JAPAN				×
4.72	AR	9-289164	11/04/97	JAPAN				×
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
4.2	AW	N. SHIMOMURA, et al., "OPTICAL COLUMN OF THEMASK-SCAN EB MASK WRITER TEST STAND", Vol. 4066, pgs. 605-612, SPIE, 2000						
	AX							
	AY							
	AZ		Additional References sheet(s) attached					
Examiner	Date Considered 6/17/04						17/64	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in								
conformance and not considered. Include copy of this form with next communication to applicant.								